Description

SUPERFET II MOSFET is ON Semiconductor's brand-new high voltage super-junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low on-resistance and lower gate charge performance. This technology is tailored to minimize conduction loss, provide superior switching performance, and withstand extreme dv/dt rate and higher avalanche energy. Consequently, SUPERFET II MOSFET Easy drive series helps manage EMI issues and allows for easier design implementation.

Features

- 650 V @ T_J = 150°C
- Typ. $R_{DS(on)} = 160 \text{ m}\Omega$
- Ultra Low Gate Charge (Typ. $Q_g = 63 \text{ nC}$)
- Low Effective Output Capacitance (Typ. Coss.eff = 178 pF)
- 100% Avalanche Tested
- These Devices are Pb-Free and are RoHS Compliant

Applications

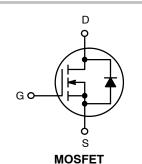
- Computing / Display Power Supplies
- Telecom / Server Power Supplies
- Industrial Power Supplies
- Lighting / Charger / Adapter



ON Semiconductor®

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V _{DSS}	R _{DS(ON)} MAX	I _D MAX
600 V	190 m Ω @ 10 V	20.6 A

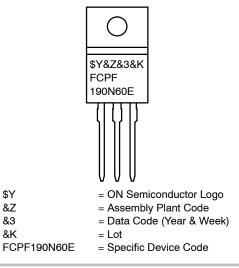






TO-220F Ultra Narrow Lead CASE 221BN

MARKING DIAGRAM



ORDERING INFORMATION

See detailed ordering and shipping information on page 2 of this data sheet.

Symbol	Parameter Drain to Source Voltage		Value	Unit V	
V _{DSS}			600		
V _{GSS}	Gate to Source Voltage	– DC	±20	V	
		– AC (f > 1 Hz)	±30		
I _D	Drain Current	– Continuous (T _C = 25°C)	T _C = 25°C) 20.6*	А	
		– Continuous (T _C = 100°C)	13.1*		
I _{DM}	Drain Current	- Pulsed (Note 1)	61.8*	А	
E _{AS}	Single Pulsed Avalanche Energy (Note 2) Avalanche Current (Note 2)		400	mJ	
I _{AS}			4.0	А	
E _{AR}	Repetitive Avalanche Energy (Note 1)	etitive Avalanche Energy (Note 1)		mJ	
dv/dt	Peak Diode Recovery dv/dt (Note 3)		20	V/ns	
	MOSFET dv/dt		100		
PD	Power Dissipation	(T _C = 25°C)	39	W	
		– Derate Above 25°C	0.31	W/°C	
T _J , T _{STG}	Operating and Storage Temperature R	Operating and Storage Temperature Range		°C	
ΤL	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds		300	°C	

MOSFET MAXIMUM RATINGS (T_C = 25°C, Unless otherwise noted)

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.
*Drain current limited by maximum junction temperature.
1. Repetitive rating: pulse width limited by maximum junction temperature.
2. I_{AS} = 4 A, V_{DD} = 50 V, R_G = 25 Ω, starting T_J = 25°C.
3. I_{SD} ≤ 10 A, di/dt ≤ 200 A/µs, V_{DD} ≤ BV_{DSS}, starting T_J = 25°C.

THERMAL CHARACTERISTICS

Symbol	Parameter	Value	Unit
R _{0JC} Thermal Resistance, Junction to Case, Max.		3.2	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient, Max.	62.5	°C/W

PACKAGE MARKING AND ORDERING INFORMATION

Part Number	Top Marking	Package	Shipping
FCPF190N60E-F154	FCPF190N60E	TO-220F (Pb-Free)	50 Units / Tube

ELECTRICAL CHARACTERISTICS ($T_C = 25^{\circ}C$ unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
OFF CHARACT	ERISTICS					
BV _{DSS}	Drain to Source Breakdown Voltage	V_{GS} = 0 V, I_{D} = 10 mA, T_{J} = 25 °C	600	-	-	V
		V_{GS} = 0 V, I_{D} = 10 mA, T_{J} = 150°C	650	-	-	V
$\Delta \text{BV}_{\text{DSS}}$ / $\Delta \text{T}_{\text{J}}$	Breakdown Voltage Temperature Coefficient	I _D = 10 mA, Referenced to 25°C	-	0.67	-	V/°C
BV_{DS}	Drain-Source Avalanche Breakdown Voltage	$V_{GS} = 0 \text{ V}, \text{ I}_{D} = 20 \text{ A}$	-	700	-	V
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 480 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$	-	-	1.0	μA
		V_{DS} = 480 V, T_{C} = 125°C	-	-	10	
I _{GSS}	Gate to Body Leakage Current	V_{GS} = ±20 V, V_{DS} = 0 V	-	-	±100	nA
ON CHARACTE	RISTICS	-				
V _{GS(th)}	Gate Threshold Voltage	V_{GS} = V_{DS} , I_D = 250 μ A	2.5	-	3.5	V
R _{DS(on)}	Static Drain to Source On Resistance	V _{GS} = 10 V, I _D = 10 A	-	0.16	0.19	Ω
9 FS	Forward Transconductance	V _{DS} = 20 V, I _D = 10 A	-	20	-	S
DYNAMIC CHA	RACTERISTICS	·			•	
C _{iss}	Input Capacitance	$V_{DS} = 25 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ f} = 1 \text{ MHz}$	-	2385	3175	pF
C _{oss}	Output Capacitance		-	1795	2396	pF
C _{rss}	Reverse Transfer Capacitance	1		110	165	pF
C _{oss}	Output Capacitance	$V_{DS} = 380 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	-	42	-	pF
C _{oss (eff.)}	Effective Output Capacitance	$V_{DS} = 0 V$ to 480 V, $V_{GS} = 0 V$	-	178	-	pF
Q _{g(tot)}	Total Gate Charge at 10 V	$V_{DS} = 380 \text{ V}, \text{ I}_{D} = 10 \text{ A}, \text{ V}_{GS} = 10 \text{ V}$	-	63	82	nC
Q _{gs}	Gate to Source Gate Charge	(Note 4)	-	10	-	nC
Q _{gd}	Gate to Drain "Miller" Charge	1	-	24	-	nC
ESR	Equivalent Series Resistance	f = 1 MHz	-	5	-	Ω
SWITCHING CH	IARACTERISTICS	•	•	4		
t _{d(on)}	Turn-On Delay Time	V_{DD} = 380 V, I_{D} = 10 A, V_{GS} = 10 V,	-	23	56	ns
tr	Turn-On Rise Time	R _g = 4.7 Ω (Note 4)	_	14	38	ns
t _{d(off)}	Turn-Off Delay Time		_	101	212	ns
t _f	Turn-Off Fall Time	1	_	15	40	ns
	N DIODE CHARACTERISTICS		<u>.</u>			
IS	Maximum Continuous Source to Drain Diode Forward Current		-	-	20.2	А
I _{SM}	Maximum Pulsed Source to Drain Diode Forward Current		-	_	60.6	A
V _{SD}	Source to Drain Diode Forward Voltage	V _{GS} = 0 V, I _{SD} = 10 A	-	_	1.2	V
t _{rr}	Reverse Recovery Time	V _{DD} = 400 V, I _{SD} = 10 A,	-	308	_	ns
Q _{rr}	Reverse Recovery Charge	dl _F /dt = 100 A/μs	<u>├</u>	4.8	_	μC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Essentially independent of operating temperature typical characteristics.

Q_{rr}

TYPICAL PERFORMANCE CHARACTERISTICS

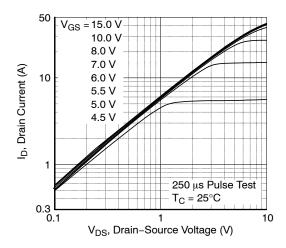


Figure 1. On–Region Characteristics

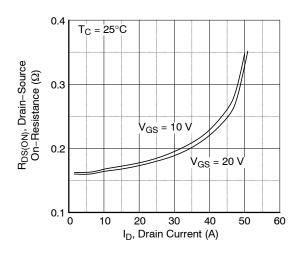


Figure 3. On–Resistance Variation vs. Drain Current and Gate Voltage

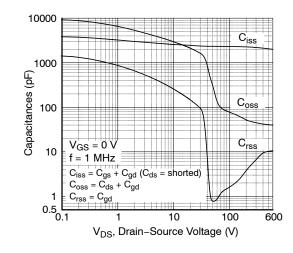


Figure 5. Capacitance Characteristics

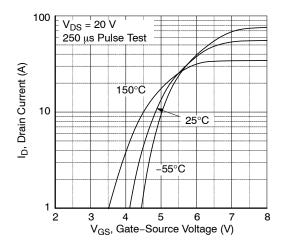


Figure 2. Transfer Characteristics

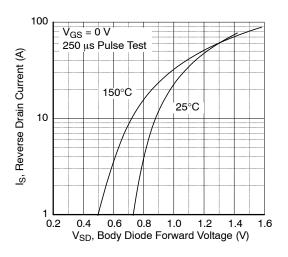


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

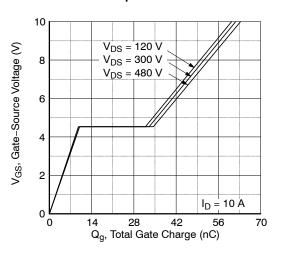
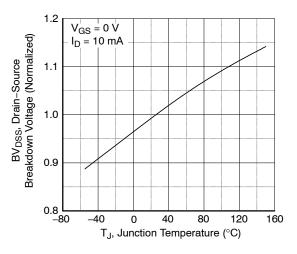
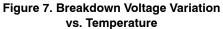


Figure 6. Gate Charge Characteristics

TYPICAL PERFORMANCE CHARACTERISTICS (continued)





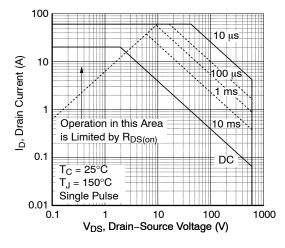


Figure 9. Maximum Safe Operating Area

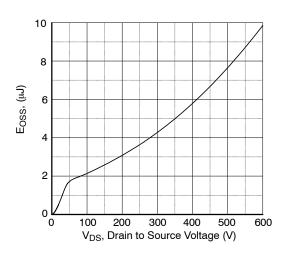


Figure 11. E_{OSS} vs. Drain-to-Source Voltage

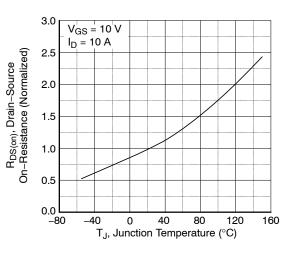


Figure 8. On–Resistance Variation vs. Temperature

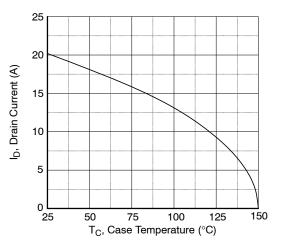


Figure 10. Maximum Drain Current vs. Case Temperature

TYPICAL PERFORMANCE CHARACTERISTICS (continued)

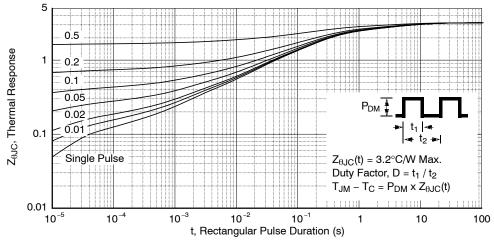


Figure 12. Transient Thermal Response Curve

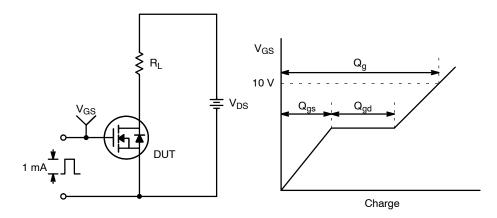


Figure 13. Gate Charge Test Circuit & Waveform

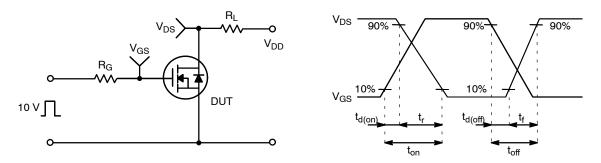


Figure 14. Resistive Switching Test Circuit & Waveforms

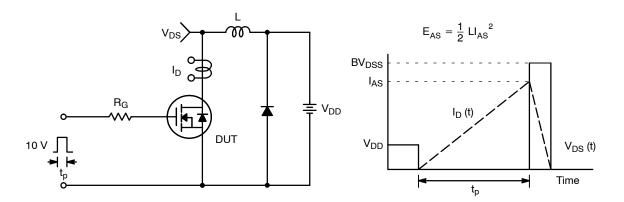


Figure 15. Unclamped Inductive Switching Test Circuit & Waveforms

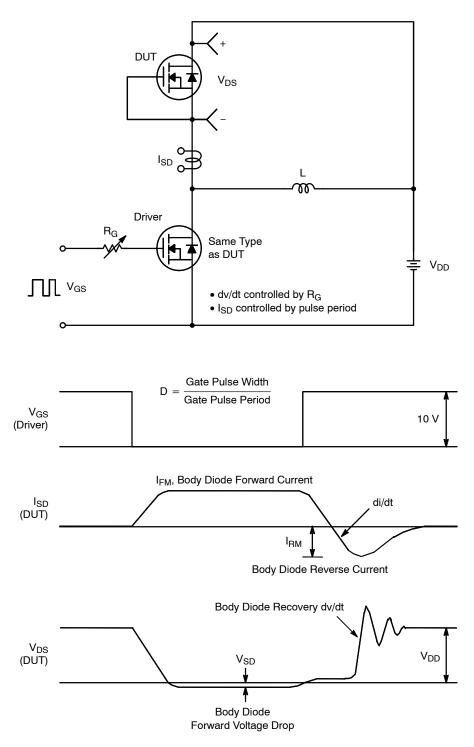


Figure 16. Peak Recovery dv/dt Test Circuit & Waveforms

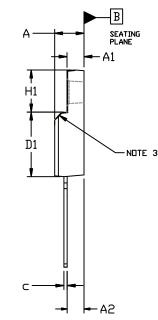
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PACKAGE DIMENSIONS

TO-220 FULLPACK, 3-LEAD CASE 221BN ISSUE O

NDTES

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- 2. CONTROLLING DIMENSION: MILLIMETERS
- 3. CONTOUR UNCONTROLLED IN THIS AREA.
- 4. DIMENSIONS EXCLUDE BURRS, MOLD FLASH, AND TIE BAR PROTRUSIONS.



	MILLIMETERS			
DIM	MIN.	NDM.	MAX.	
Α	4.60	4.70	4.80	
A1	2.50	2.60	2.70	
A2	2.47	2.57	2.67	
b	0.56	0.63	0.69	
b2			0.90	
с	0.46	0.53	0.59	
D	15.80	16.00	16.20	
D1	9.58	9.68	9.78	
Е	10.00	10.20	10.40	
e	2.54 BSC			
H1	6.32 REF			
L	13.45	13.60	13.75	
L1	1.70	1.80	1.90	
Ρ	3.00	3.10	3.20	
Q	3.25	3.35	3.45	

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